

RELIABILITY DATA

LTC5549

9/22/2015

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
QFN	154 154	1450	1450	154.00 154.00	0 0

• HIGHLY ACCELERATED STRESS TEST AT +130°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
QFN	77 77	1450	1450	293.76 293.76	0 0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
QFN	141 141	1450	1450	47.38 47.38	0 0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
QFN	154 154	1450	1450	154.00 154.00	0 0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
QFN	154 154	1450	1450	154.00 154.00	0 0

• HIGH TEMPERATURE BAKE AT 150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
QFN	154 154	1450	1450	154.00 154.00	0 0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 76.45 FITS

(3) Mean Time Between Failures in Years = 1,493

(4) Assumes 20X Acceleration from 85°C to +130°C

Note: 1 FIT = 1 Failure in One Billion Hours.